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	Examiner Jaisle, Cecilia M	Art Unit 1624

SEARCHED			
Class	Subclass	Date	Examiner
514	403, 404	10/10/2007	Cecilia Jaisle
548	373.1, 375.1	10/10/2007	Cecilia Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner